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## NTE3089 Optoisolator AC Input, Silicon NPN Phototransistor Output

### **Description:**

The NTE3089 consists of two gallium arsenide LEDs connected in inverse parallel and coupled with a silicon phototransistor in a 6-Lead DIP type package.

### **Features:**

- AC or Polarity Insensitive Inputs
- Fast Switching Speeds
- Built-In Reverse Polarity Input Protection
- High Isolation Voltage
- High Isolation Resistance
- I/O Compatible with Integrated Circuits

**Absolute Maximum Ratings:** ( $T_A = +25^\circ\text{C}$ , unless otherwise specified)

#### **Infrared Emitting Diode (LED)**

Continuous Forward Current, $I_F$ .....	60mA
Peak Forward Current (Pulse Width = 1μs, 330pps), $I_F$ .....	±1A
Power Dissipation ( $T_A = +25^\circ\text{C}$ , Note 1), $P_D$ .....	100mW
Derate Above 25°C .....	1.33mW/°C

#### **Phototransistor**

Collector-Emitter Voltage, $V_{CEO}$ .....	30V
Collector-Base Voltage, $V_{CBO}$ .....	70V
Emitter-Base Voltage, $V_{EBO}$ .....	5V
Continuous Collector Current, $I_C$ .....	100mA
Power Dissipation ( $T_A = +25^\circ\text{C}$ ), $P_D$ .....	300mW
Derate Above 25°C .....	4.0mW/°C
Power Dissipation ( $T_A = +25^\circ\text{C}$ , Note 1), $P_D$ .....	500mW
Derate Above 25°C .....	6.7mW/°C

#### **Total Device**

##### **Steady-State Isolation Voltage (Input-to-Output)**

Peak .....	1500V
RMS .....	1060V

##### **Surge Isolation Voltage (Input-to-Output)**

Peak .....	2500V
RMS .....	1770V

Operating Temperature Range,  $T_J$  .....

−55° to +150°C

Storage Temperature Range,  $T_{stg}$  .....

−55° to +150°C

Lead Temperature (During Soldering for 10sec),  $T_L$  .....

+250°C

Note 1.  $T_C$  indicates Collector lead temperature 1/32" from case.



**Electrical Characteristics:** ( $T_A = +25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
<b>Infrared Emitting Diode (LED)</b>						
Forward Voltage	$V_F$	$I_F = \pm 10\text{mA}$	—	—	1.5	V
Capacitance	$C_J$	$V_R = 0, f = 1\text{MHz}$	—	—	100	pF
<b>Phototransistor</b>						
Collector–Base Breakdown Voltage	$V_{(\text{BR})\text{CBO}}$	$I_C = 100\mu\text{A}, I_F = 0$	70	—	—	V
Collector–Emitter Breakdown Voltage	$V_{(\text{BR})\text{CEO}}$	$I_C = 10\text{mA}, I_F = 0$	30	—	—	V
Emitter–Base Breakdown Voltage	$V_{(\text{BR})\text{EBO}}$	$I_E = 100\mu\text{A}, I_F = 0$	5	—	—	V
Collector Dark Current	$I_{\text{CEO}}$	$V_{CE} = 10\text{V}, I_F = 0$	—	—	100	nA
<b>Coupled</b>						
DC Current Transfer Ratio	CTR	$V_{CE} = 10\text{V}, I_F = \pm 10\text{mA}$	20	—	—	%
Collector–Emitter Saturation Voltage	$V_{CE(\text{sat})}$	$I_C = 0.5\text{mA}, I_F = \pm 10\text{mA}$	—	—	0.4	V
Isolation Resistance	$R_{(I-O)}$	$V_{(I-O)} = 500\text{V}$ , Note 2	100	—	—	GΩ

Note 2. Tests of Input-to-Output isolation current resistance, and capacitance are performed with the input terminals (diode) shorted together and the output terminals (transistors) shorted together.



